

## 2<sup>nd</sup> generation thinQ!<sup>™</sup> SiC Schottky Diode

#### Features:

### **Applications:**

SMPS, PFC, snubber

- Revolutionary Semiconductor Material -Silicon Carbide
- Switching Behaviour Benchmark
- No Reverse Recovery / No Forward Recovery
- Temperature Independent Switching Behaviour
- Qualified According to JEDEC<sup>1)</sup> Based on Target Applications

Chip Type	V <sub>R</sub>	<b>I</b> Fn	Die Size	Package
IDC04S60CE	600V	4A	1.146 x 0.968 mm <sup>2</sup>	sawn on foil

### **Mechanical Parameters**

	-	-			
Die size		1.146x 0.968			
Area total		1.11			
Anode pad size		0.909 x 0.731			
Thickness		355 µi			
Wafer size		100	mm		
Max. possible chips per	wafer	6190	6190		
Passivation frontside		Photoimide			
Pad metal		3200 nm AlSiCu			
Backside metal		Ni Ag –system			
Die bond		Electrically conductive epoxy glue and soft solder			
Wire bond		Al, ≤500µm			
Reject ink dot size		Ø 0.65mm; max 1.2mm			
	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month			
Storage environment <sup>1)</sup>	for open MBB bags	Acc. to IEC60721-3-3: Atmosphere >99% Nitroger gas, Humidity <25%RH, Temperature 17°C – 25°C,			

<sup>1)</sup> Designed for storage conditions according to Infineon TR14 (Application Note "Storage of Products Supplied by Infineon Technologies)

Designed for climate condition under operation according to IEC60721-3-3, class 3K3

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#### Maximum Ratings

Parameter	Symbol	Condition	Value	Unit	
Repetitive peak reverse voltage	V <sub>RRM</sub>	<i>T</i> <sub>vj</sub> =25 °C	600	v	
DC blocking voltage	V <sub>DC</sub>		600	V	
Continuous forward current, limited by <i>T</i> <sub>vjmax</sub>	I <sub>F</sub>	<i>T</i> <sub>vj</sub> < 150°C	4		
Surge non repetitive forward current,	,	$T_{\rm C}$ =25°C, $t_{\rm P}$ =10 ms	32		
sine halfwave	I <sub>F,SM</sub>	<i>T</i> <sub>C</sub> =150°C, <i>t</i> <sub>P</sub> =10 ms		A	
Repetitive peak forward current, limited by thermal resistance <i>R</i> <sub>th</sub>	I <sub>F,RM</sub>	$T_{\rm C} = 100^{\circ}{\rm C}, \ T_{\rm vj} = 150^{\circ}{\rm C}, \ D=0.1$	18		
Non-repetitive peak forward current	I <sub>F,max</sub>	$T_{\rm C} = 25^{\circ} {\rm C}, t_{\rm P} = 10 {\rm \mu s}$	132		
i <sup>2</sup> t value	$\int i^2 dt$	$T_{\rm C} = 25^{\circ} {\rm C}, \ t_{\rm P} = 10 {\rm ms}$	5.1	– A <sup>2</sup> s	
i t value	J <sup>i</sup> al	$T_{\rm C}$ =150°C, $t_{\rm P}$ =10 ms			
Operating junction and storage temperature range	T <sub>vj</sub> , T <sub>stg</sub>		-55+175	°C	

### Static Characteristics (tested on wafer), $T_{vj}$ = 25 °C

Parameter	Symbol	Conditions	Value			Unit
			min.	Тур.	max.	Unit
Reverse current	I <sub>R</sub>	V <sub>R</sub> =600V		0.5	50	μA
Diode forward voltage	V <sub>F</sub>	I <sub>F</sub> =4A		1.7	1.9	V

### Static Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			Unit
Faiallelei	Symbol	conations	min.	Тур.	max.	Unit
Reverse current	I <sub>R</sub>	$V_{\rm R}$ =600V, $T_{\rm vj}$ =150°C		2	500	μA
Diode forward voltage	V <sub>F</sub>	<i>I</i> <sub>F</sub> =4A, <i>T</i> <sub>vj</sub> =150°C		2	2.4	V



Parameter	Symbol	Conditions		Value			Unit
	Symbol			min.	Тур.	max.	Onit
Total capacitive charge <sup>3)</sup>	Q <sub>c</sub>	$I_{\rm F} <= I_{\rm F,max}$	<i>T</i> <sub>vj</sub> =150°C		8		nC
Switching time <sup>2)</sup>	t <sub>c</sub>	di/dt=200A/μs V <sub>R</sub> =400V	<i>T</i> <sub>vj</sub> =150°C			<10	ns
			$V_{\rm R}$ =1 V		130		
Total capacitance	С	f=1MHz	V <sub>R</sub> =300V		20		pF
_			V <sub>R</sub> =600V		20		

#### Dynamic Characteristics (not subject to production test - verified by design / characterization)

<sup>1)</sup> J-STD20 and JESD22 <sup>2)</sup>  $t_c$  is the time constant for the capacitive displacement current waveform (independent from  $T_{vj}=150$ °C,  $I_{LOAD}$  and di/dt), different from  $t_{rr}$ , which is dependent on  $T_{vj}=150$ °C,  $I_{LOAD}$ , di/dt. No reverse recovery time constant  $t_{rr}$  due to absence of minority carrier inject. <sup>3)</sup> Only capacitive charge occurring, guaranteed by design (independent from  $T_{vj}$ ,  $I_{LOAD}$  and di/dt).

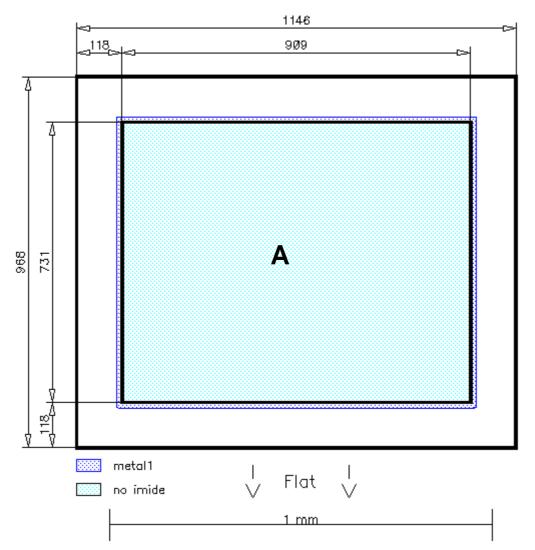
#### **Further Electrical Characteristics**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	IDT04S60C	Rev. 2.1
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**Chip Drawing** 



Die-Size 1146 um x 968 um

### A: Anode pad

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#### Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Version	Subjects (major changes since last revision)	Date

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